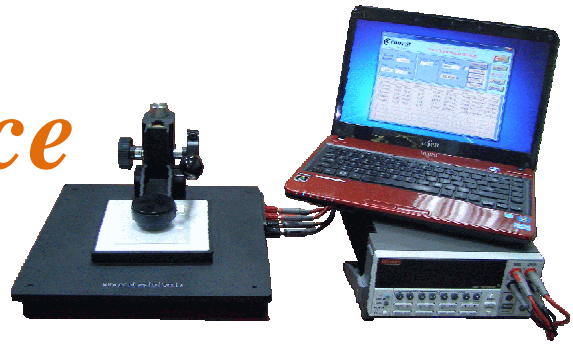


Sheet Resistance Measurement

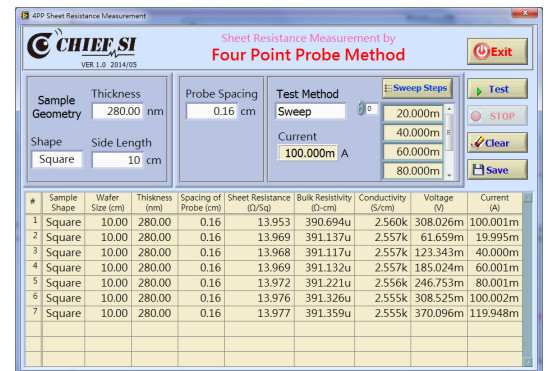


Rapid, Intuitive Four-Point Probe Sheet Resistance Measurement :

By using four-point probe, measuring the Sheet Resistance of different kinds of conductor, semi-conductor in sheet, film or bulk form. The high accuracy four-point probe station combined with a rapid, accurate SMU (Source Measure Unit) provides a high quality, easy to use system to measure the Sheet Resistance of thin film materials for various industrial fields such as semi-conductor, solar panel, OLED, MEMS, Fuel Cells, etc.

System Features :

- Intuitive and easy to use software user interface (UI).
- Accurate measuring the sheet resistance of sample.
- Single or multiple point measuring under constant current.
- Derive the Bulk Resistivity and Conductivity by input the thickness of sample.
- Saving test data by .CSV format for easily handling data.
- Operate with Keithley 2400 SMU by default. Capable of customize software for various SMUs and ohmmeters.



Specifications :

Chuck size	6", 8", 12"	Measure item	Sheet Resistance, Bulk Resistivity, Conductivity
Sample geometry	Circle or Square	Interface	RS-232 or GPIB
Head Up/Down	16mm	Language	English
Correct factor	Thickness & Geometry	PC Requirements	CPU:P4, HD:1GB, USB 2.0
Probe Pin Material	BeCu (or Tungsten Carbide)	Monitor Requirements	1280*800 resolution
Probe Pin Spacing	40mil, 50mil, 62.5mil	O.S. Supported	Windows XP, WIN 7
Probe Pin Spring	45grams, 85grams, 180grams	SMU Support	Keithley 2400 / 2401



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